STN3N40K3



N-channel 400 V, 3 Ω typ., 1.8 A SuperMESH3™ Power MOSFET in a SOT-223 package

Datasheet - production data

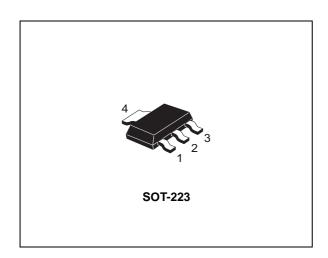
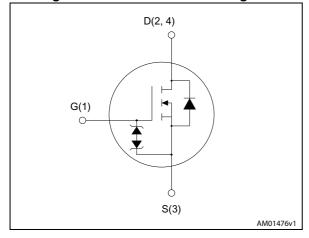


Figure 1. Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max	I _D	P _{TOT}
STN3N40K3	400V	3.4 Ω	1.8 A	3.3W

- 100% avalanche tested
- Extremely high dv/dt capability
- Gate charge minimized
- · Very low intrinsic capacitance
- Improved diode reverse recovery characteristics
- Zener-protected

Application

· Switching applications

Description

This SuperMESH3™ Power MOSFET is the result of improvements applied to STMicroelectronics' SuperMESH™ technology, combined with a new optimized vertical structure. This device boasts an extremely low onresistance, superior dynamic performance and high avalanche capability, rendering it suitable for the most demanding applications.

Table 1. Device summary

Order code	Marking	Package	Packaging
STN3N40K3	3N40K3	SOT-223	Tape and reel

Contents STN3N40K3

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STN3N40K3 Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain source voltage	400	V
V _{GS}	Gate-source voltage	± 30	V
I _D	Drain current continuous T _C = 25 °C	1.8 ⁽¹⁾	Α
I _D	Drain current continuous T _C = 100 °C	1 ⁽¹⁾	Α
I _{DM} ⁽²⁾	Drain current pulsed	7.2	Α
I _{AR} (3)	Avalanche current, repetitive or not repetitive	0.6	Α
E _{AS} (4)	Single pulse avalanche energy	45	mJ
P _{TOT}	Total dissipation at T _{amb} = 25 °C	3.3	W
dv/dt (5)	Peak diode recovery voltage slope	12	V/ns
E _{SD}	Gate-source human body model (R = 1.5 k Ω , C = 100 pF)	1	kV
T _j T _{stg}	Operating junction temperature Storage temperature	-55 to 150	°C

- 1. Drain current limited by maximum junction temperature.
- 2. Pulse width limited by safe operating area.
- 3. Pulse width limited by T_{Jmax}.
- 4. Starting $T_i = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V.
- 5. Isd \leq 1.8 A, di/dt \leq 400 A/ μ s, $V_{DD} \leq$ 80% $V_{(BR)DSS}$.

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-amb} ⁽¹⁾	Thermal resistance junction-amb max.	37.9	°C/W

1. When mounted on FR-4 board of 1 inch², 2oz Cu, t < 30 s

Electrical characteristics STN3N40K3

2 Electrical characteristics

(Tcase = 25 °C unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	400			V
	Zero gate voltage	$V_{GS} = 0, V_{DS} = 400 V$			1	μΑ
I _{DSS}	drain current	$V_{GS} = 0$, $V_{DS} = 400 V$, $T_C = 125 °C$			50	μΑ
I _{GSS}	Gate-body leakage current	$V_{DS} = 0, V_{GS} = \pm 20 \text{ V}$			±10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{GS} = V_{DS}$, $I_D = 50 \mu A$	3	3.75	4.5	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 0.6 A		3.1	3.4	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	165	-	pF
C _{oss}	Output capacitance	$V_{DS} = 50 \text{ V, f} = 1 \text{ MHz,}$	-	17	-	pF
C _{rss}	Reverse transfer capacitance	$V_{GS} = 0$	-	3	-	pF
C _{oss(er)} ⁽¹⁾	Equivalent output capacitance energy related	V _{DS} = 0 to 320 V, V _{GS} = 0	-	9	-	pF
C _{oss(tr)} ⁽²⁾	Equivalent output capacitance time related	V _{DS} = 0 to 320 V, V _{GS} = 0	1	14	1	pF
R _g	Instrinsic gate resistance	f=1 MHz open drain	-	10	-	Ω
Qg	Total gate charge	V _{DD} = 320 V, I _D = 1.8 A,	1	11	1	nC
Q_{gs}	Gate-source charge	V _{GS} = 10 V	-	2	-	nC
Q_{gd}	Gate-drain charge	(see Figure 18)	-	7	-	nC

^{1.} Is defined as a constant equivalent capacitance giving the same charging time as $C_{\rm oss}$ when $V_{\rm DS}$ increases from 0 to 80% $V_{\rm DSS}$

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^{2.} Is defined as a constant equivalent capacitance giving the same storage energy as $\rm C_{oss}$ when $\rm V_{DS}$ increases from 0 to 80% $\rm V_{DSS}$

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t _{d(on)}	Turn on delay time		-	7	-	ns
t _r	Rise time	$V_{DD} = 200 \text{ V}, I_{D} = 0.6,$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$	-	8	-	ns
t _{d(off)}	Turn off delay time	(see Figure 17)	-	18	-	ns
t _f	Fall time		-	14	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		1.8	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		7.2	Α
V _{SD} (2)	Forward on voltage	I _{SD} = 0.6 A, V _{GS} = 0	-		1.5	V
t _{rr}	Reverse recovery time	I _{SD} = 1.8 A, di/dt = 100 A/μs	1	145		ns
Q _r	Reverse recovery charge	V _{DD} = 60 V	-	490		nC
I _{RRM}	Reverse recovery current	(see <i>Figure 20</i>)	-	7		Α
t _{rr}	Reverse recovery time	I _{SD} = 1.8 A, di/dt = 100 A/μs	-	166		ns
Q _{rr}	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 \text{ °C}$	-	580		nC
I _{RRM}	Reverse recovery current	(see Figure 20)	-	7		Α

^{1.} Pulse width limited by safe operating area.

^{2.} Pulsed: pulse duration = $300 \mu s$, duty cycle 1.5%

Electrical characteristics STN3N40K3

2.1 Electrical characteristics

Figure 2. Safe operating area

Figure 3. Thermal impedance

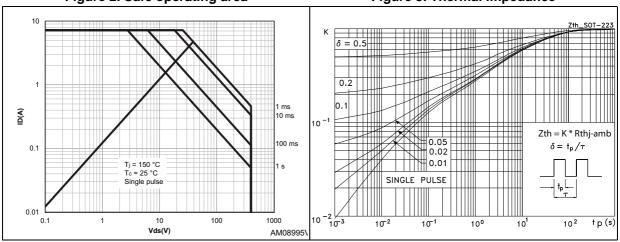


Figure 4. Output characteristics

Figure 5. Transfer characteristics

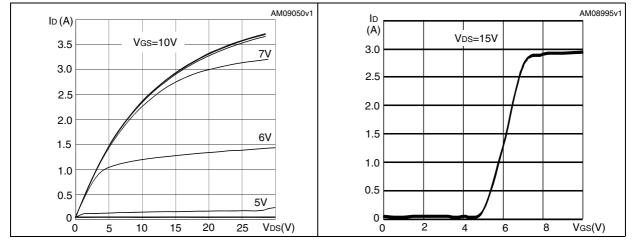


Figure 6. Gate charge vs gate-source voltage

8

V_{GS} (V) 12 V_{DD=320}V (Ω) 4.2 4.0 3.8 3.6 3.4 3.2

10 Qg(nC)

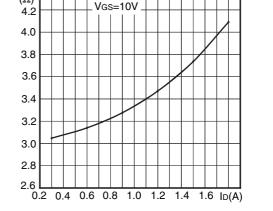


Figure 7. Static drain-source on resistance

Figure 8. Capacitance variations

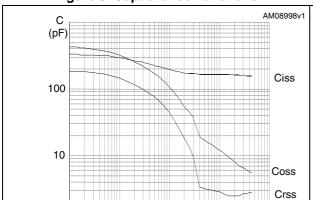


Figure 9. Output capacitance stored energy

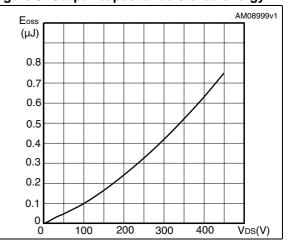


Figure 10. Normalized gate threshold voltage vs. temperature

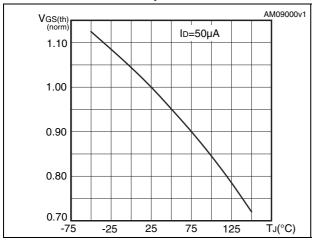
10

100

V_{DS}(V)

0.1

Figure 11. Normalized on resistance vs. temperature



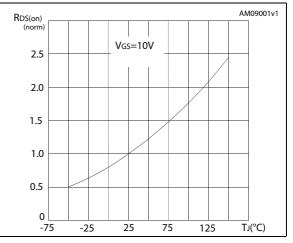
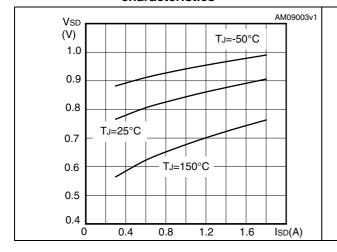
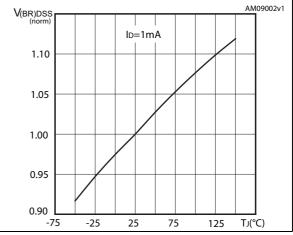


Figure 12. Source-drain diode forward characteristics

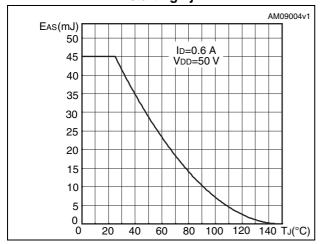
Figure 13. Normalized $V_{(BR)DSS}$ vs. temperature





Electrical characteristics STN3N40K3

Figure 14. Maximum avalanche energy vs. starting Tj



STN3N40K3 Test circuits

3 Test circuits

Figure 15. Switching times test circuit for resistive load

Figure 16. Gate charge test circuit

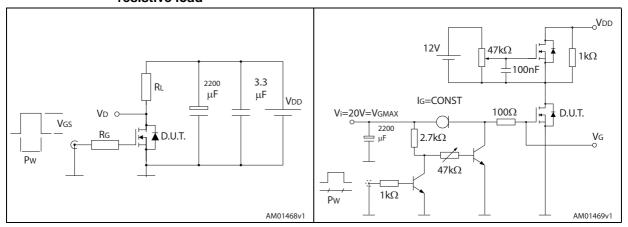


Figure 17. Switching times test circuit for resistive load

Figure 18. Gate charge test circuit

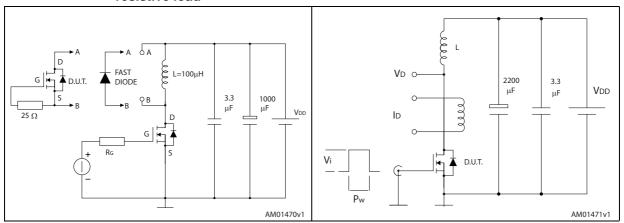
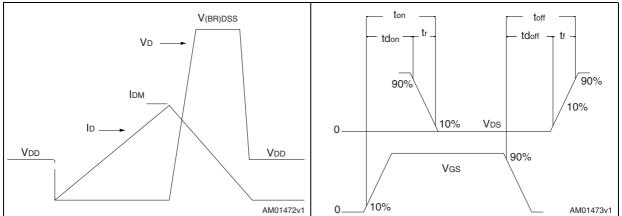


Figure 19. Unclamped inductive waveform

Figure 20. Switching time waveform



4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.



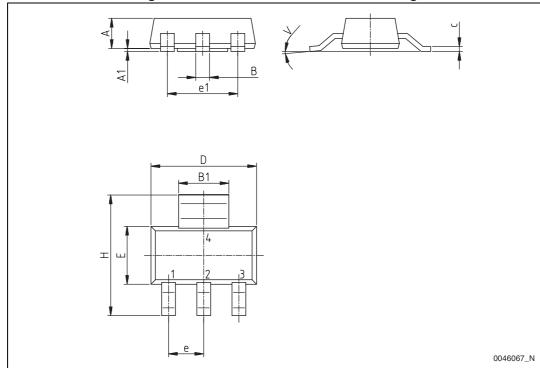


Figure 21. SOT-223 mechanical data drawing

Table 8. SOT-223 mechanical data

Dim		mm				
Dim.	Min.	Тур.	Max.			
Α			1.80			
A1	0.02		0.10			
В	0.60	0.70	0.85			
B1	2.9	3.0	3.15			
С	0.24	0.26	0.35			
D	6.30	6.50	6.70			
е		2.30	6.70			
e1		4.60				
Е	3.30	3.50	3.70			
Н	6.70	7.0	7.30			
V			10°			

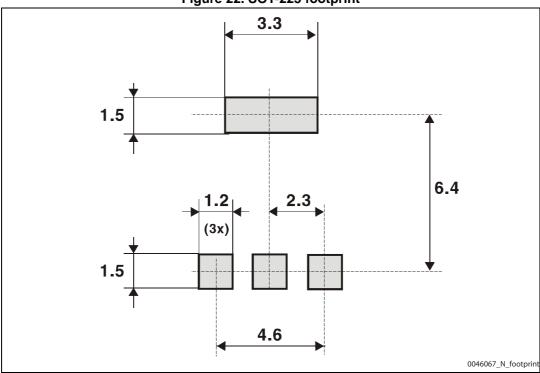


Figure 22. SOT-223 footprint

STN3N40K3 Revision history

5 Revision history

Table 9. Document revision history

Date	Revision	Changes
29-Jun-2010	1	First release.
08-Apr-2011	2	Document status promoted from preliminary data to datasheet.
06-Jun-2014	3	Updated silhouette, features and Figure 1: Internal schematic diagram in cover page. Updated Table 2: Absolute maximum ratings, Table 3: Thermal data, and Table 4: On /off states. Updated Figure 2: Safe operating area and Figure 6: Gate charge vs gate-source voltage. Updated Section 4: Package mechanical data. Minor text changes.

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